

**Search Notes**

Application/Control No.

10/510,591

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

KLOEN ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	678, 787, 781 and 786	6/30/2005	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	6/30/2005	C.C.